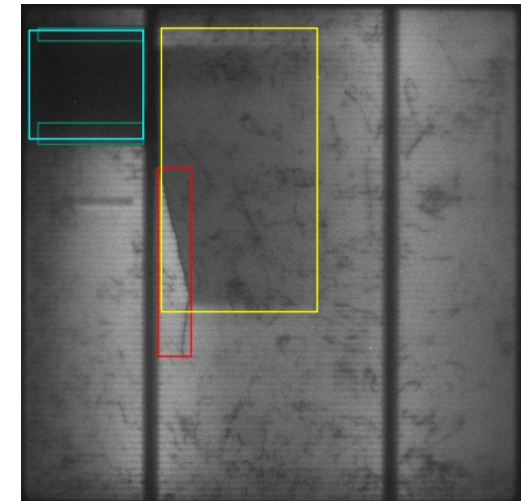




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Advanced EL inspection with predictive estimation of module power loss

Ralph Schmidt (Dipl.-Ing)
pi4_robotics GmbH Berlin

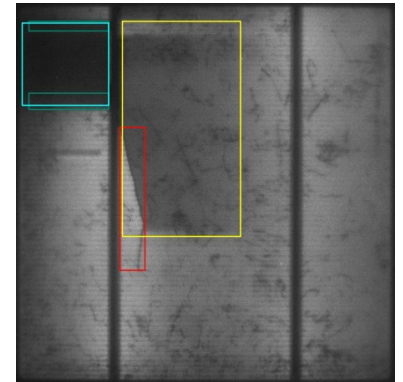




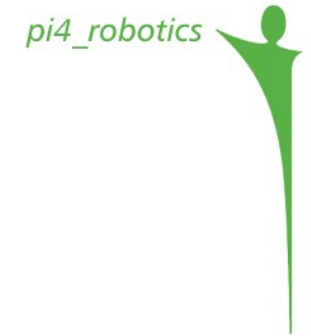
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Agenda:

- Introduction pi4
- The idea: Estimate power loss at an early stage in production
- Investigation of single cells with defects
- Estimation of Power loss for PV module
- Conclusion



Introduction pi4

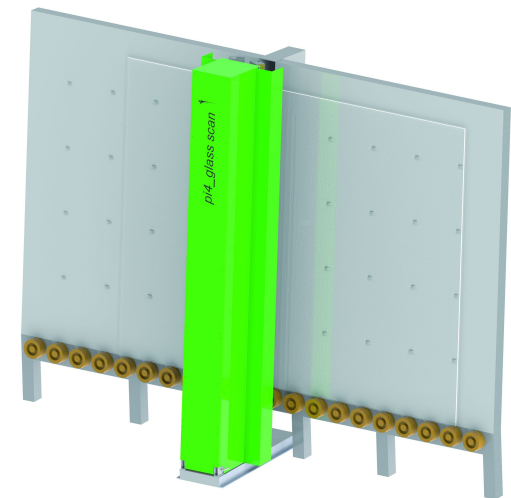


20 Years Experience as Supplier of:

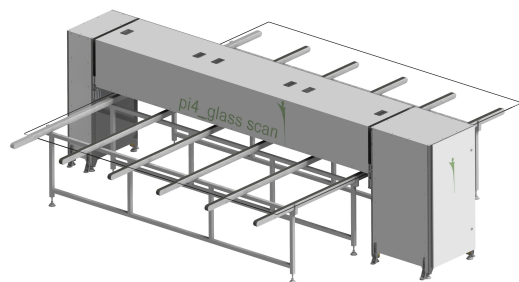
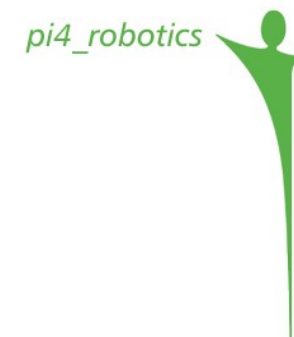
- Optical inspection systems
- Automatic handling systems
- Robotics
- Specialist for 1D, 2D and 3D optical inspection
- 45 employees in 2013
- Manufacturing location Berlin
- World wide sales activity



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Selection of pi4 systems for PV



Glass inspection



copyright pi4_robotics GmbH

Automatic inline EL-inspection



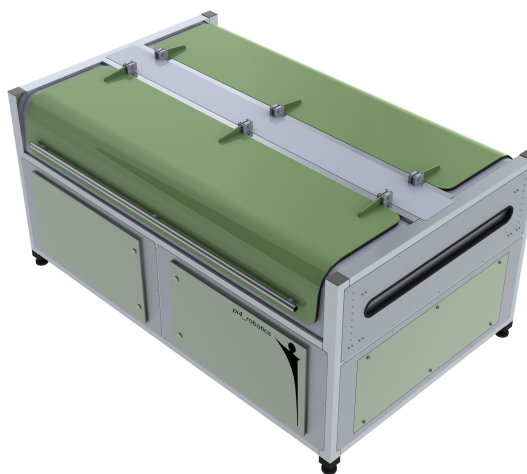
Solder inspection



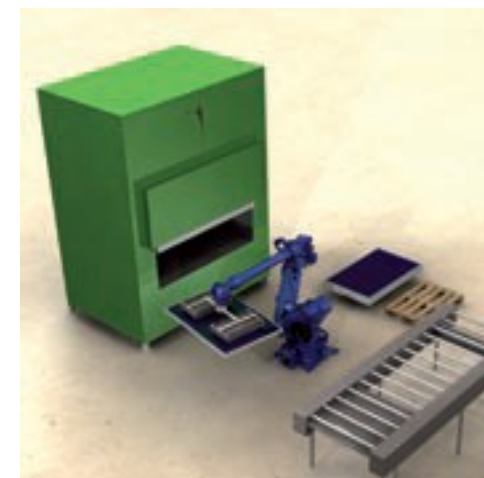
EL-string inspection



EL visual inspection system



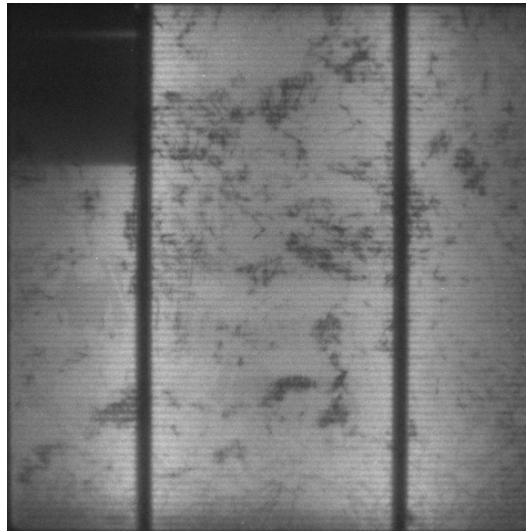
Inline EL-inspection for thin film PV



EL integrated to flasher

Why EL inspection in PV module production ?

- High consistency of module quality by EL inspection



- Cost reduction by optimizing production process (save material, increase module power)

Yield loss of a module production line today: 1% bis 2%

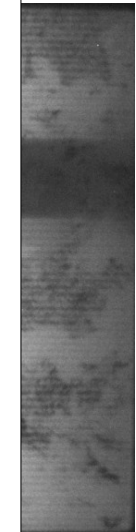
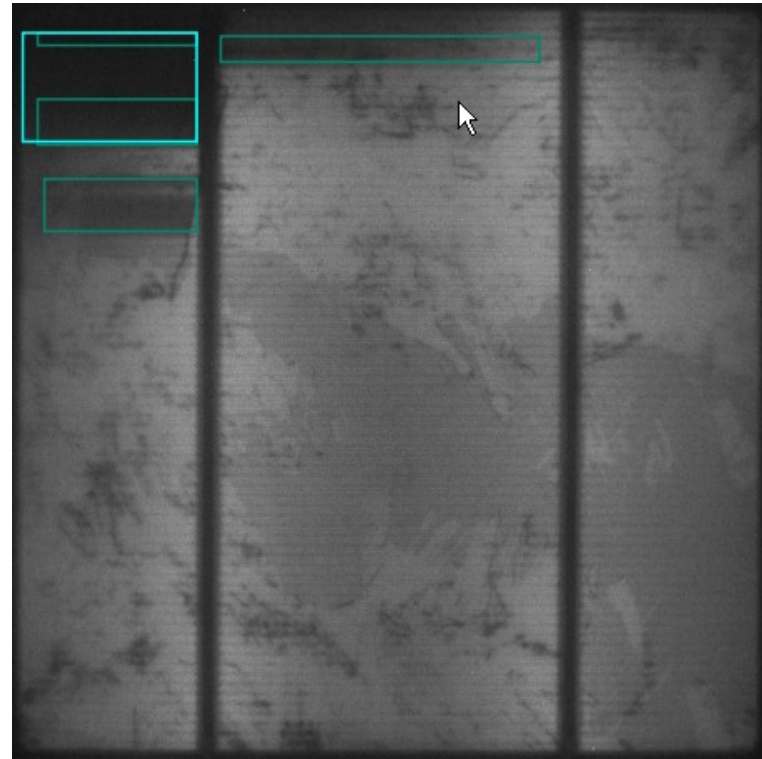
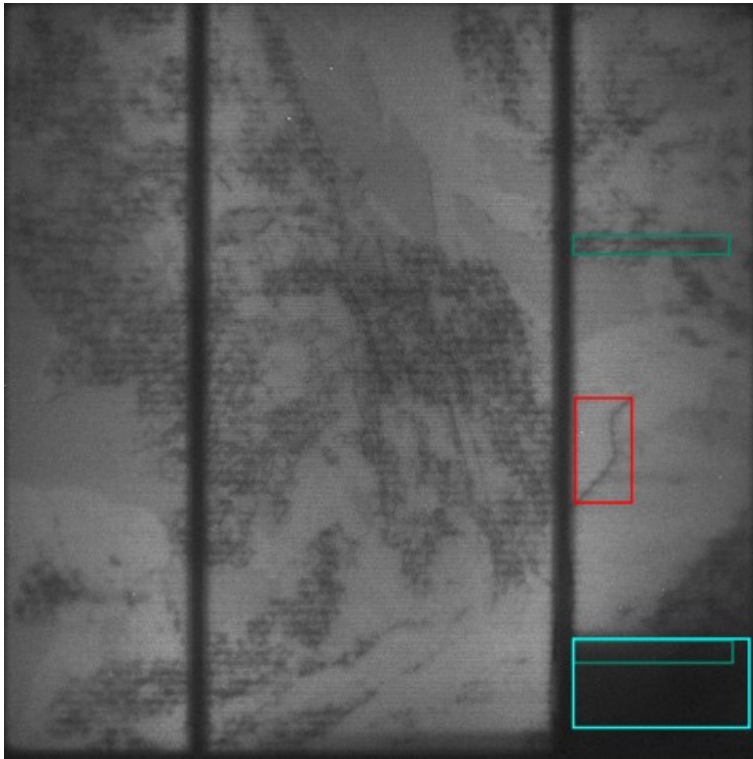
share of stringer 0.25% declared, + percentage undiscovered in production ???

share of laminator 0.20% declared, + percentage undiscovered in production ???

remaining 0.55% bis 1.55% ???

Sources ITRPV 2011 and manufacturer data

Why EL-Inspection in PV module production ?



module power)

Yield Loss of a module production line today: 1% bis 2%

share of stringer 0.25% declared, undiscovered in production ???

share of laminator 0.20% declared, undiscovered in production ???

remaining 0.55% bis 1.55% ???

Sources ITRPV 2011 and manufacturer data

Typical Quality Specification Today:

Item	Class A	Class B	Class C	Failed
No. of Micro Cracks	≤ 1 cracks / cell ≤ 1 cell / module	≤ 2 cracks / cell ≤ 5 cells / module	> 2 cracks / cell ≤ 12 cells / module	> 12 cells / module
ActiveCracks	0	1	≥ 1	≥ 2
Dark or Black Cells	0	0	0	≥ 1
Inefficient Area per Cell	$\leq 4\%$	$\leq 7\%$	$> 7\%$	$> 10\%$

It basically is counting cracks
with no relation to its significance on potential power degradation

The idea: Estimate power loss at an early stage in production

Providing a tool to

- automatically judge defects by its significance for future power generation capability of each cell
- Estimate the power loss for each cell as tested
- Estimate the power loss after an assumed load or aging
- Estimate the power loss for the complete module *)
- Perform a quality classification of the module
- Send service messages to operators such as

Classifier Message: F104: Stringer solder conveyor wear or contamination. Cells sticking to conveyor when picked up

*) based on publication of M Koentges "The risk of power loss in crystalline silicon based photovoltaic modules due to micro-cracks"

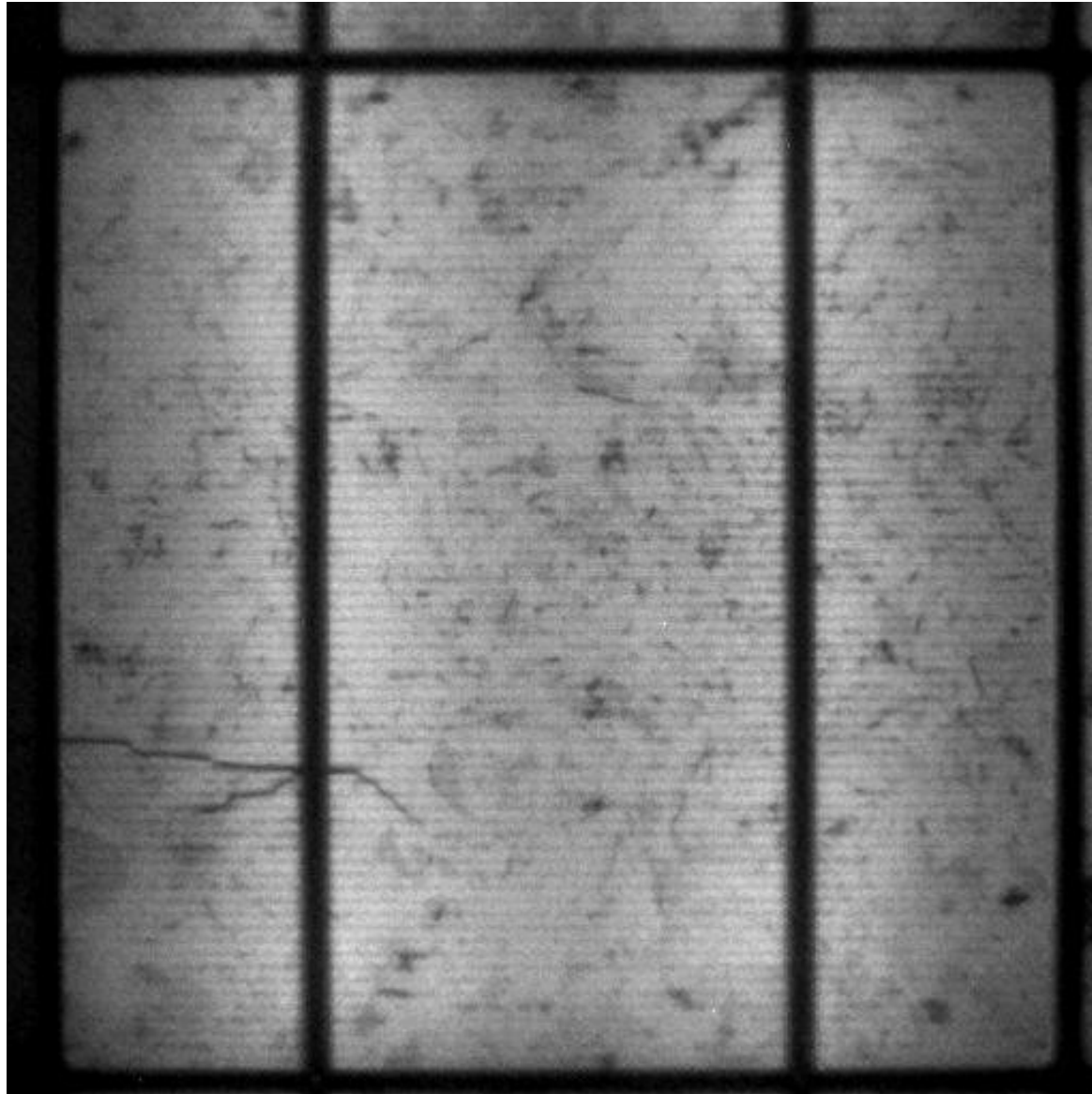
Three step approach to estimate power loss

- PL1 : power loss is calculated with the defects as detected in the EL image
- PL2 : power loss is calculated assuming all micro cracks turn into active cracks after aging process of module
- PL3 : Power loss is calculated assuming an amount of crack growth.

The amount of crack growth in reality is not known, however the user may set the software to a maximum value for the worst case when the crack propagates through the entire cell.

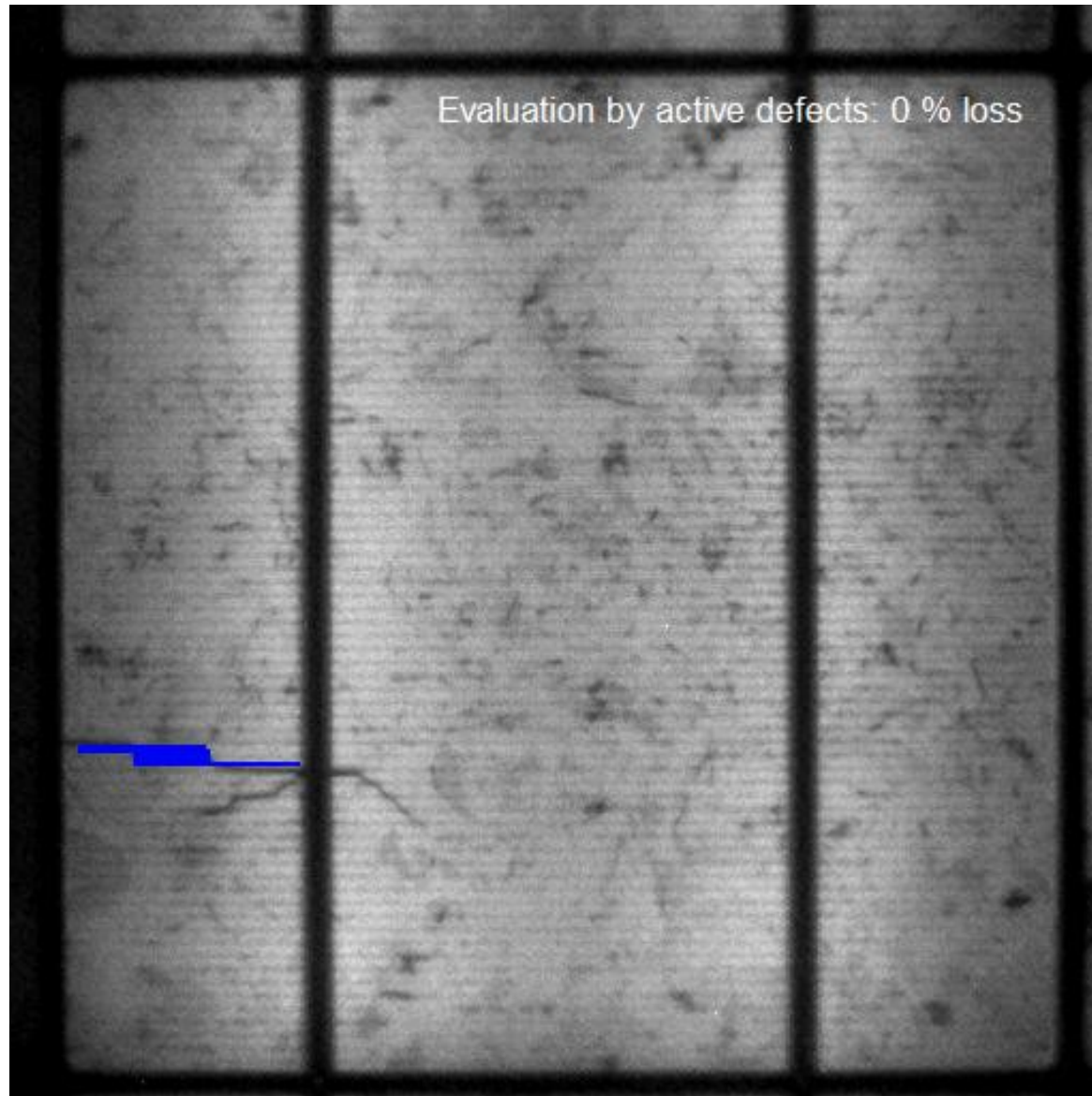
Power Loss Estimation

Original cell
image



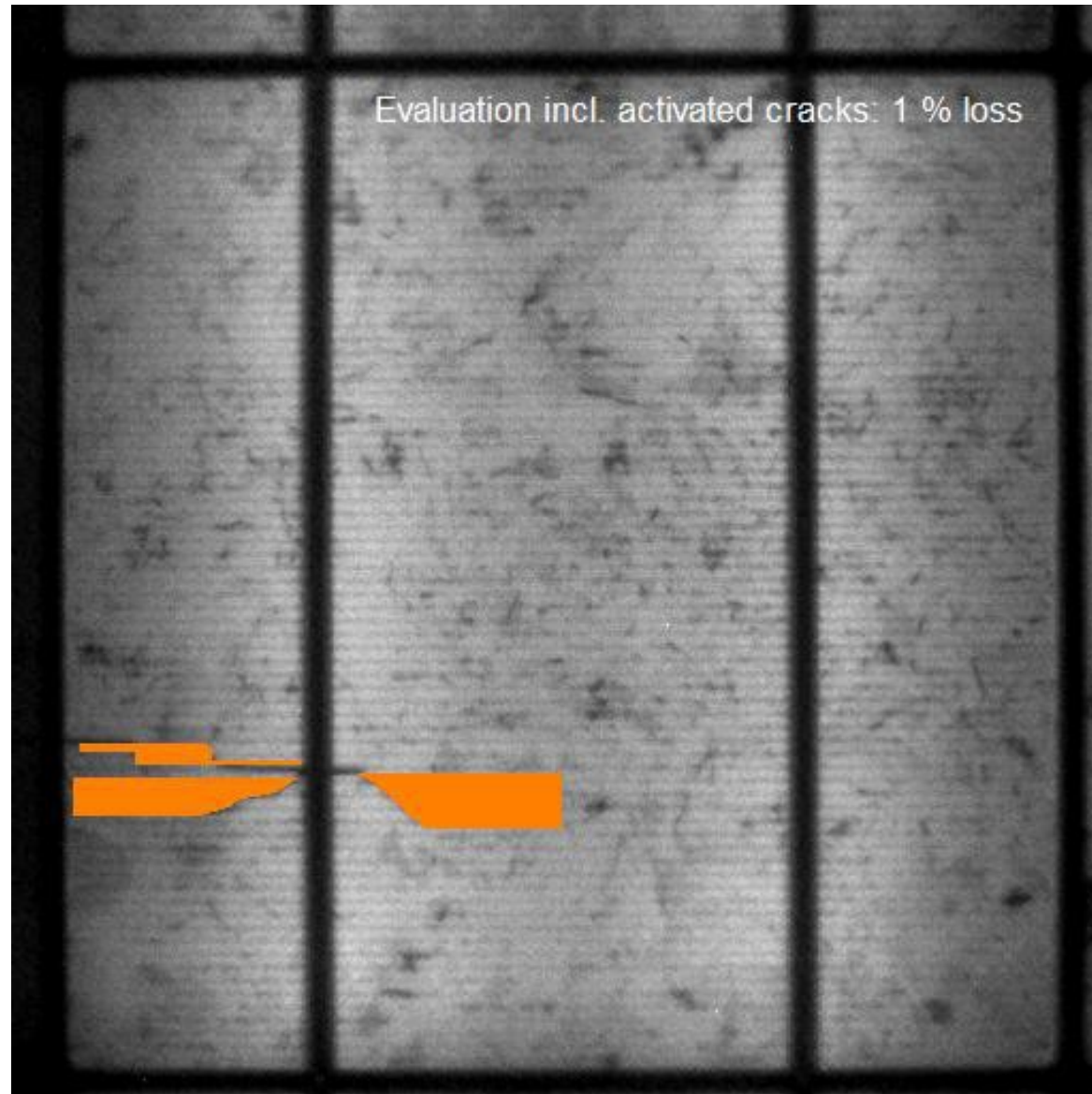
Power Loss Estimation

PL1:
All defects
showing power
loss



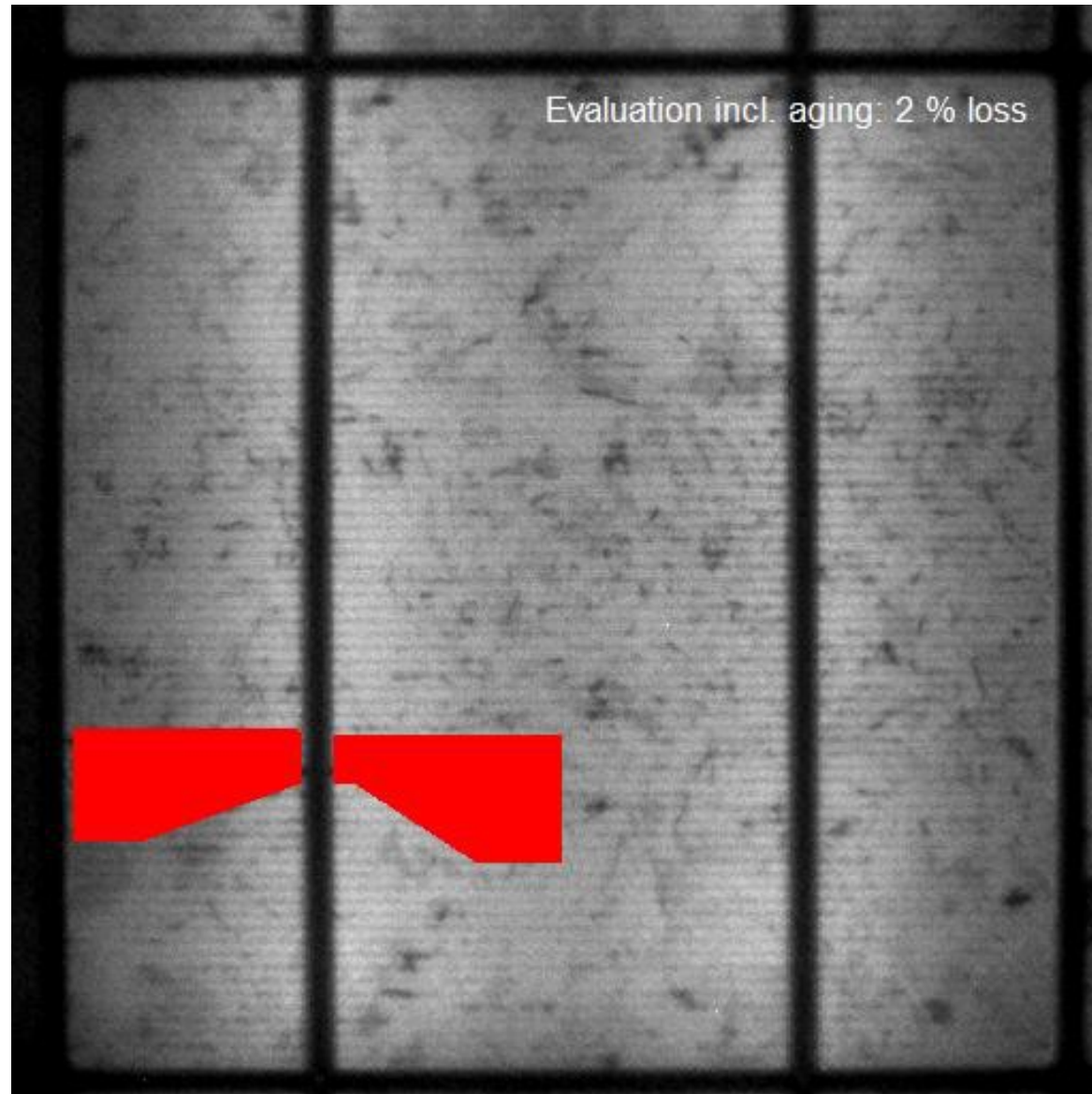
Power Loss Estimation

PL2:
All defects
showing power
loss +
micro cracks
turned into
active cracks



Power Loss Estimation

PL3:
All defects
after aging



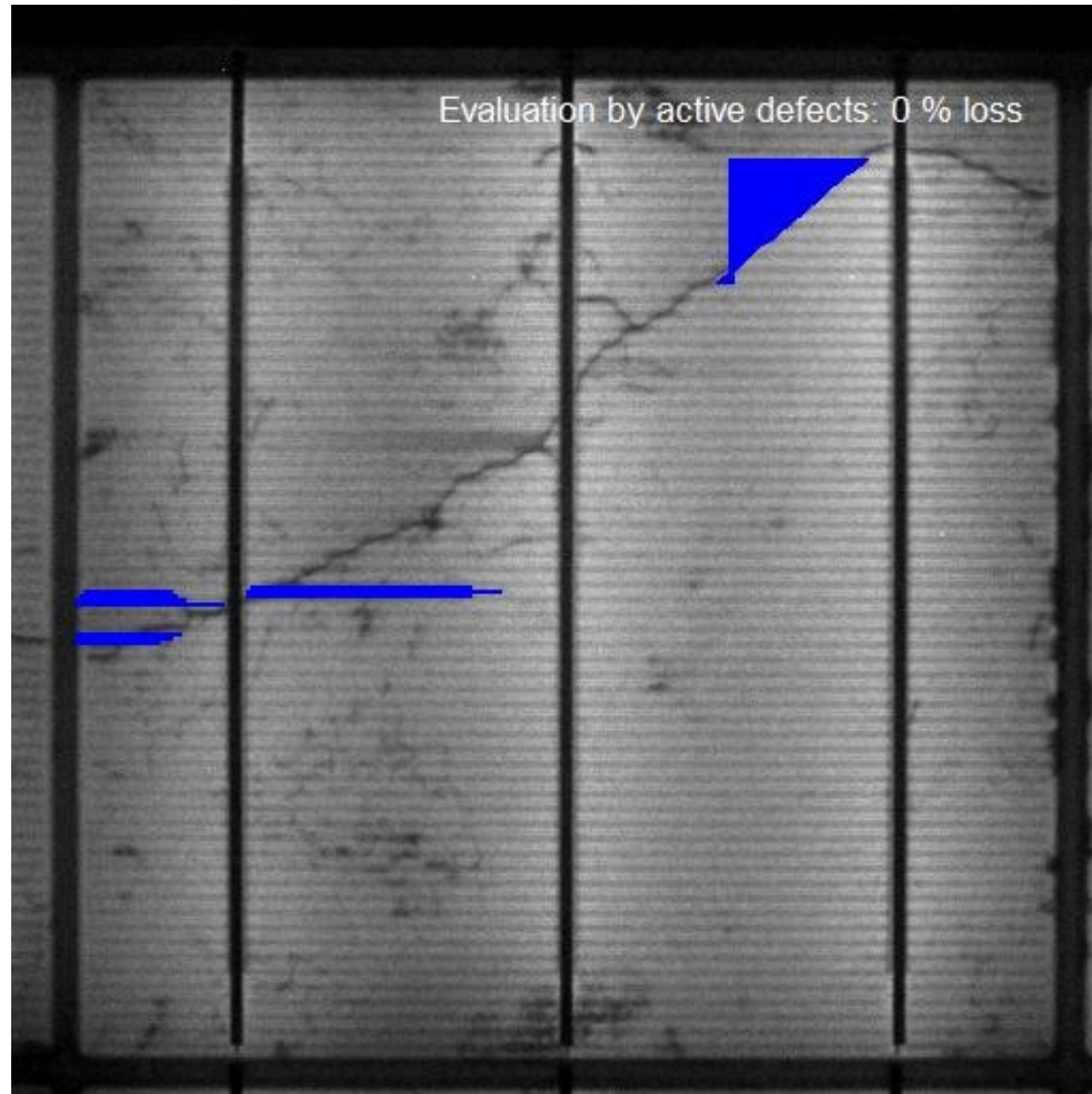
Power Loss Estimation

Original cell
image



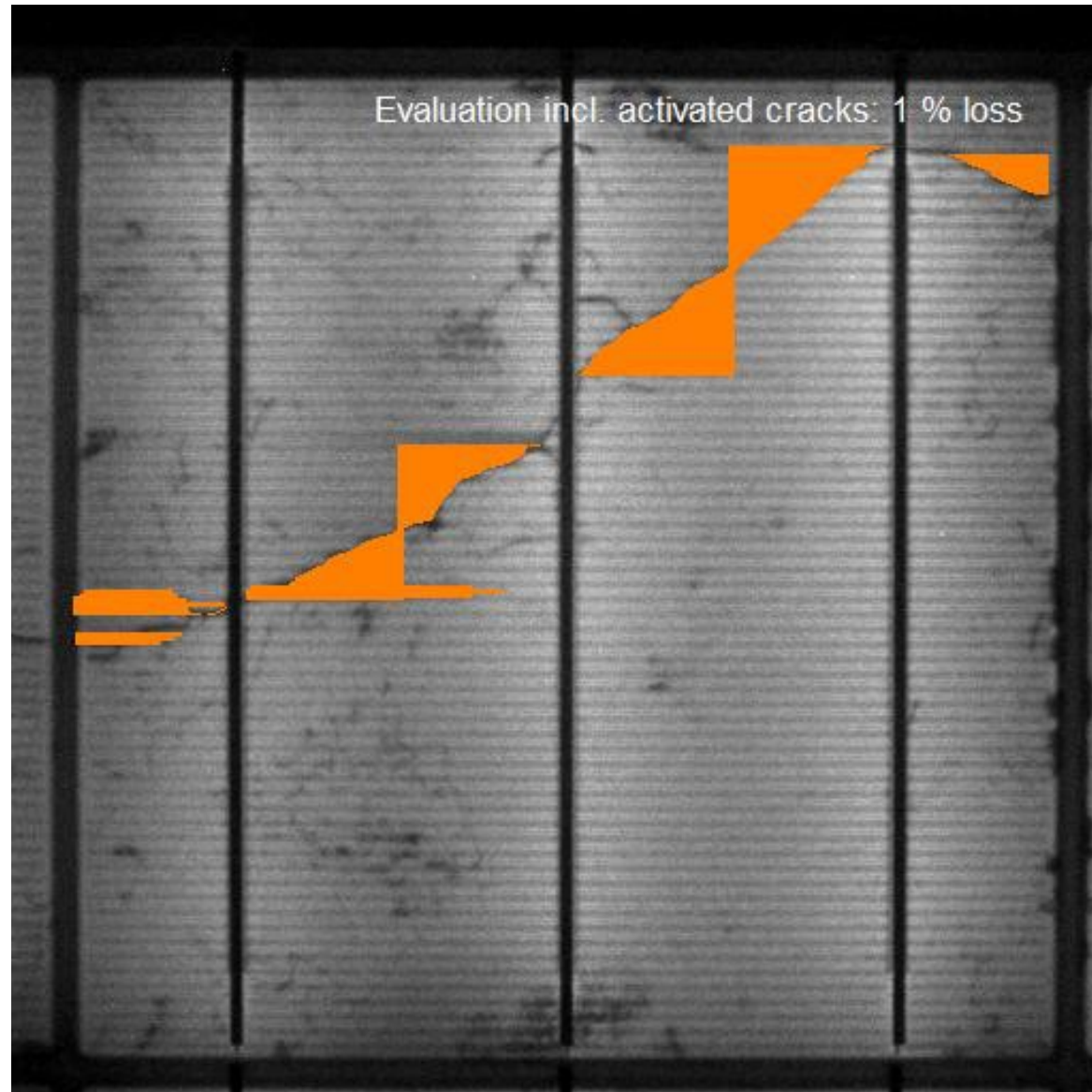
Power Loss Estimation

PL1:
All defects
showing power
loss



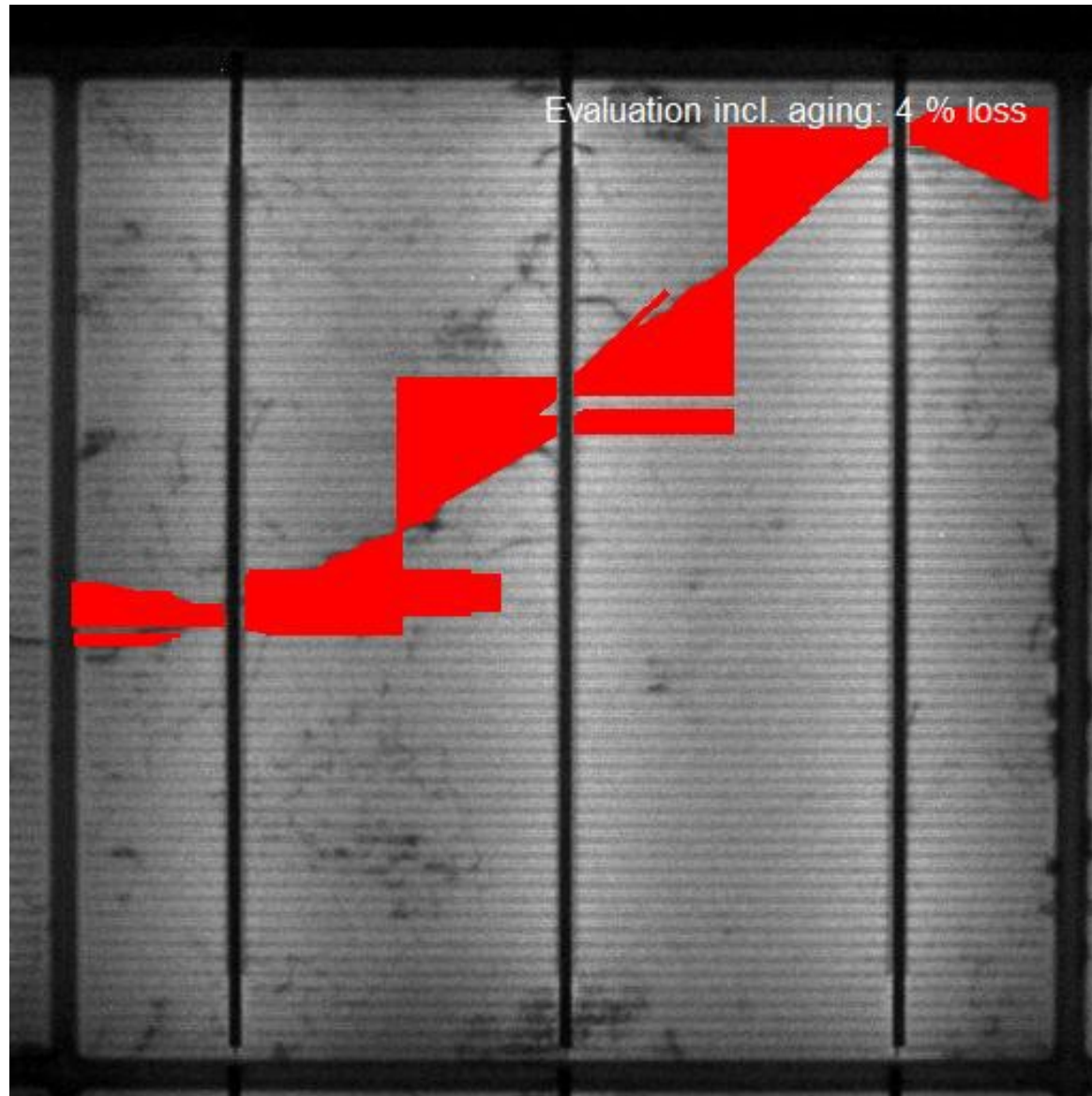
Power Loss Estimation

PL2:
All defects
showing power
loss +
micro cracks
turned into
active cracks



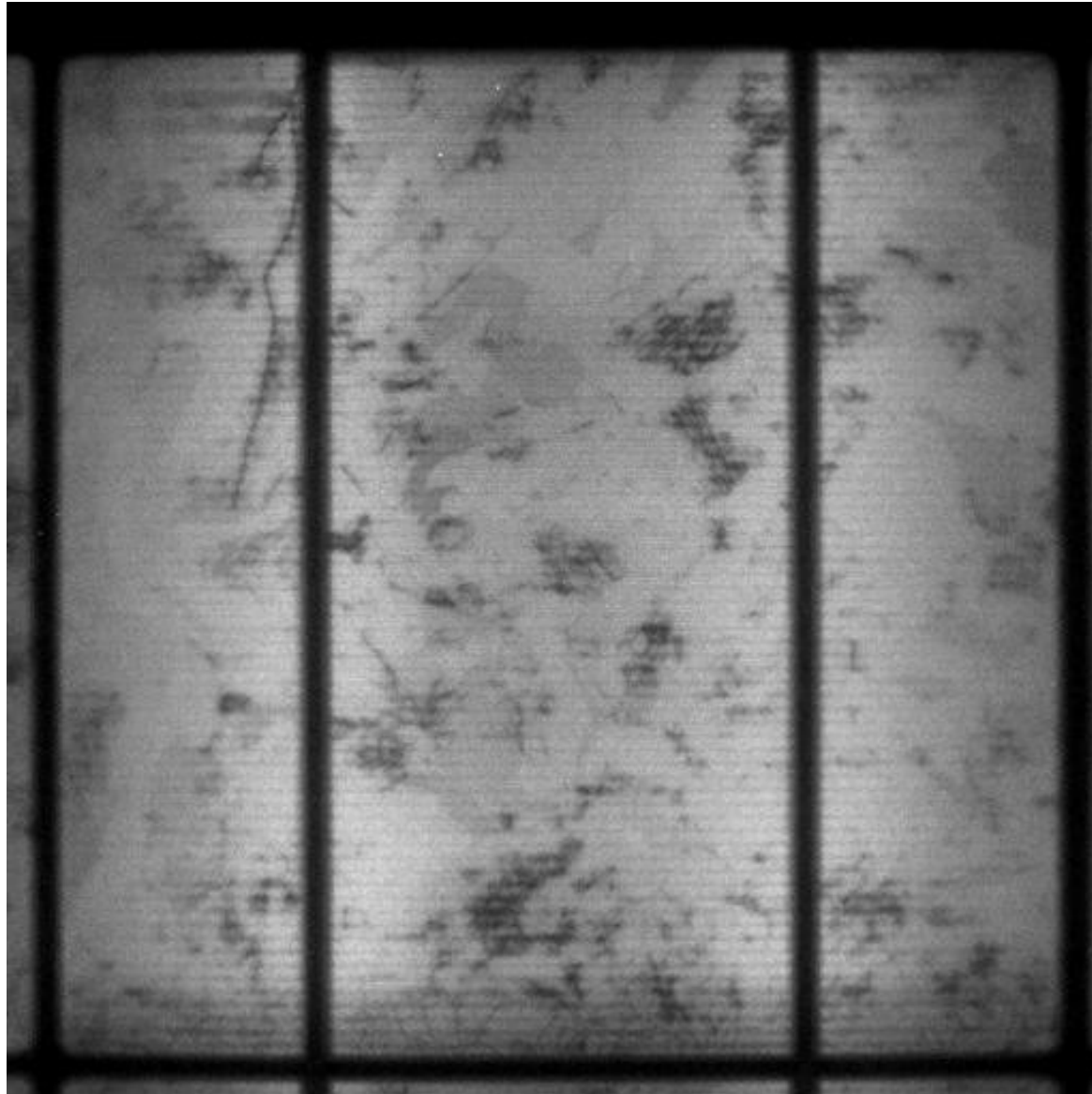
Power Loss Estimation

PL3:
All defects
after aging



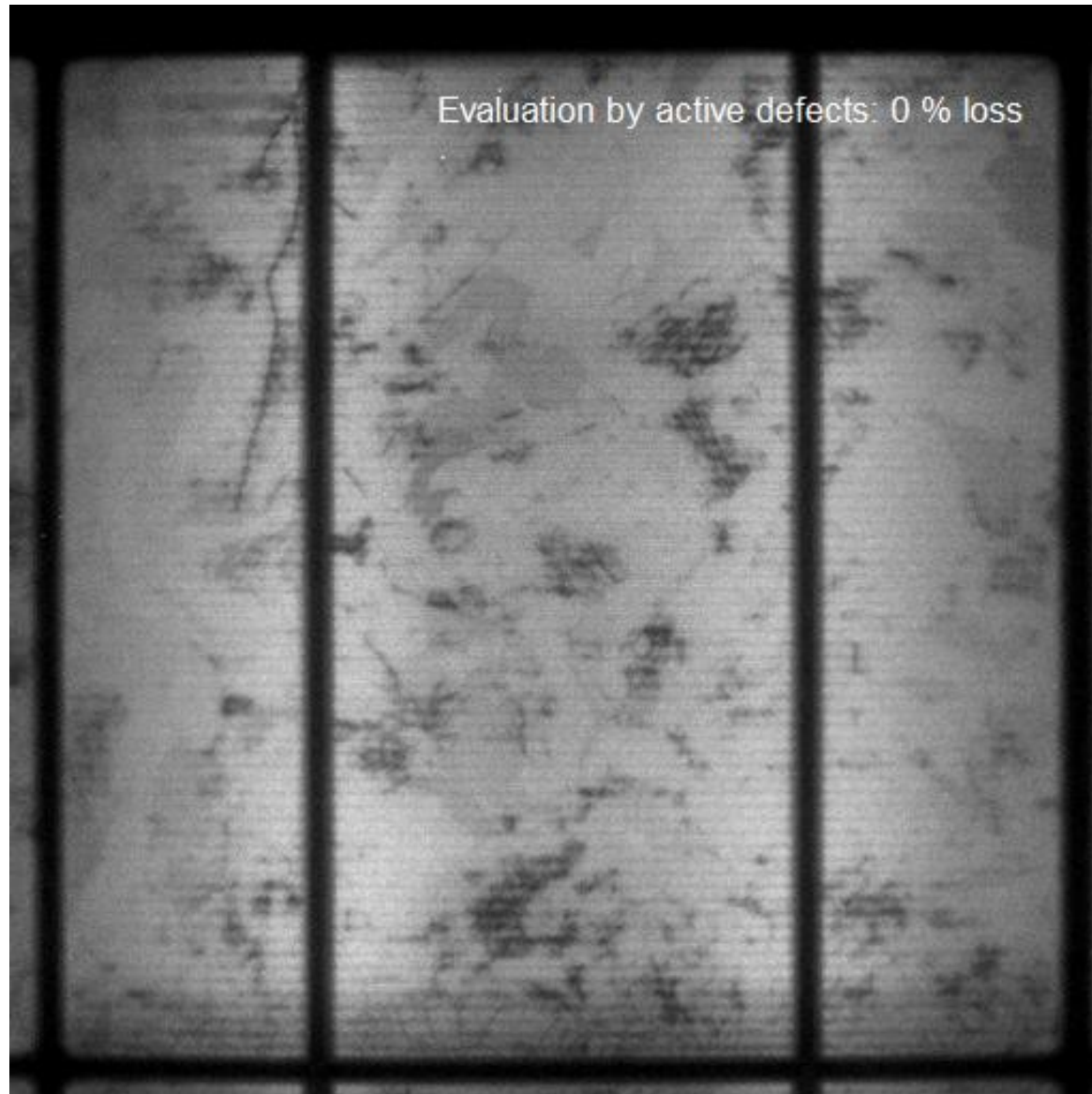
Power Loss Estimation

Original cell
image



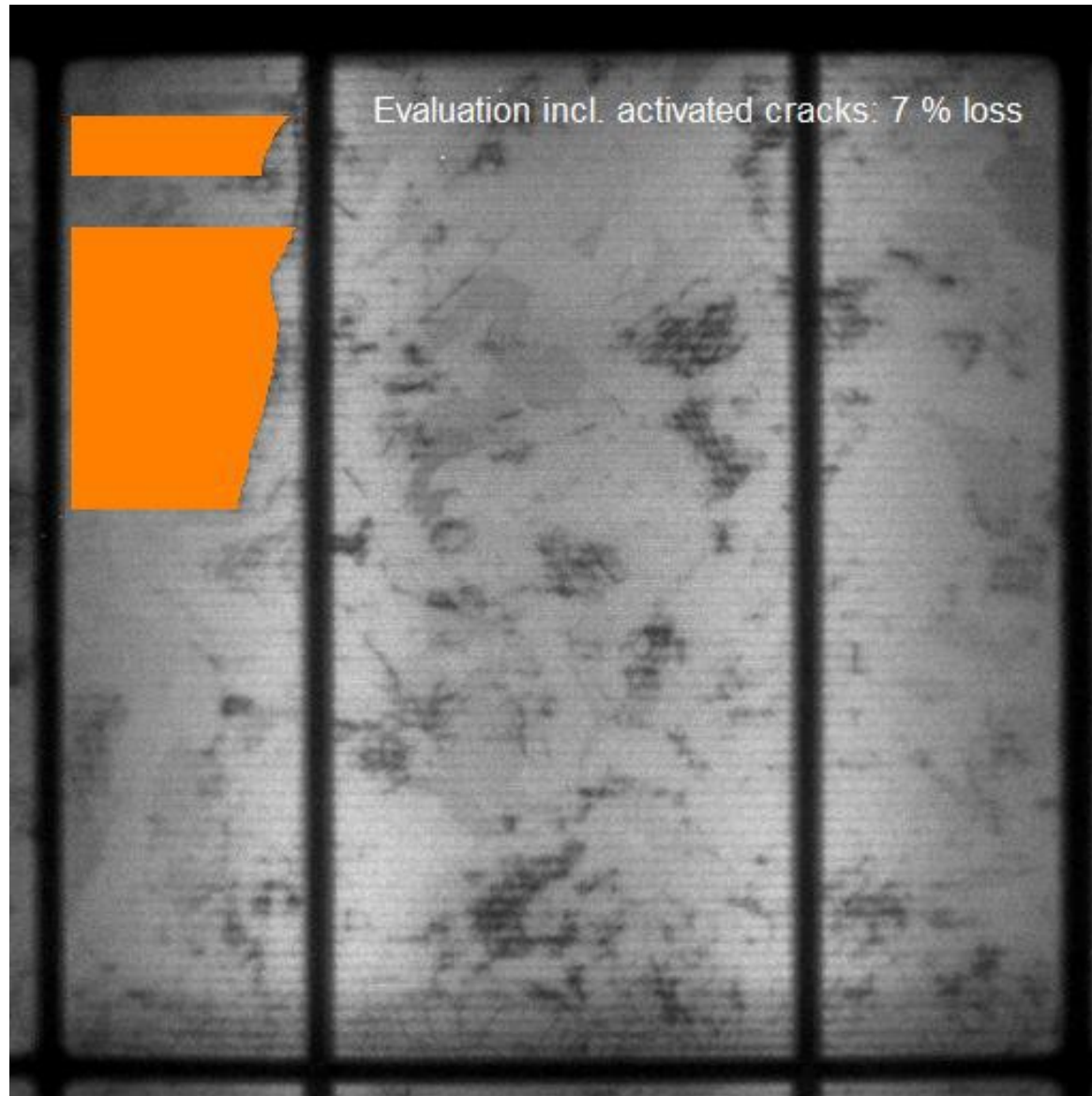
Power Loss Estimation

PL1:
All defects
showing power
loss



Power Loss Estimation

PL2:
All defects
showing power
loss +
micro cracks
turned into
active cracks

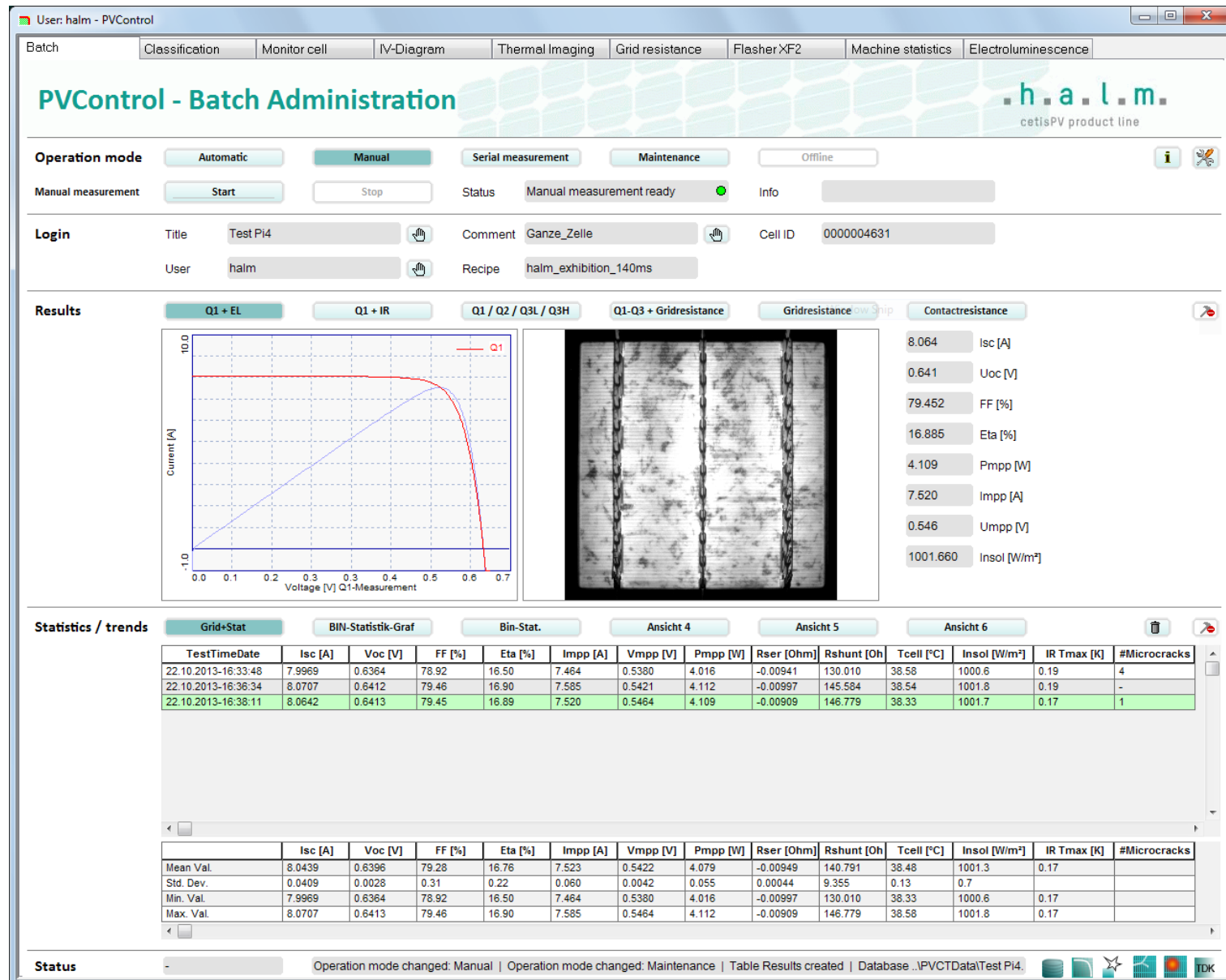
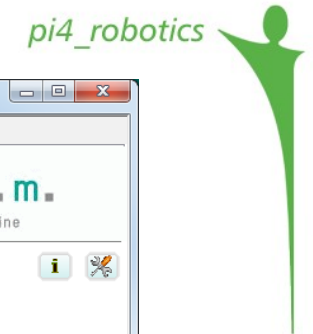


Power Loss Estimation

PL3:
All defects
after aging

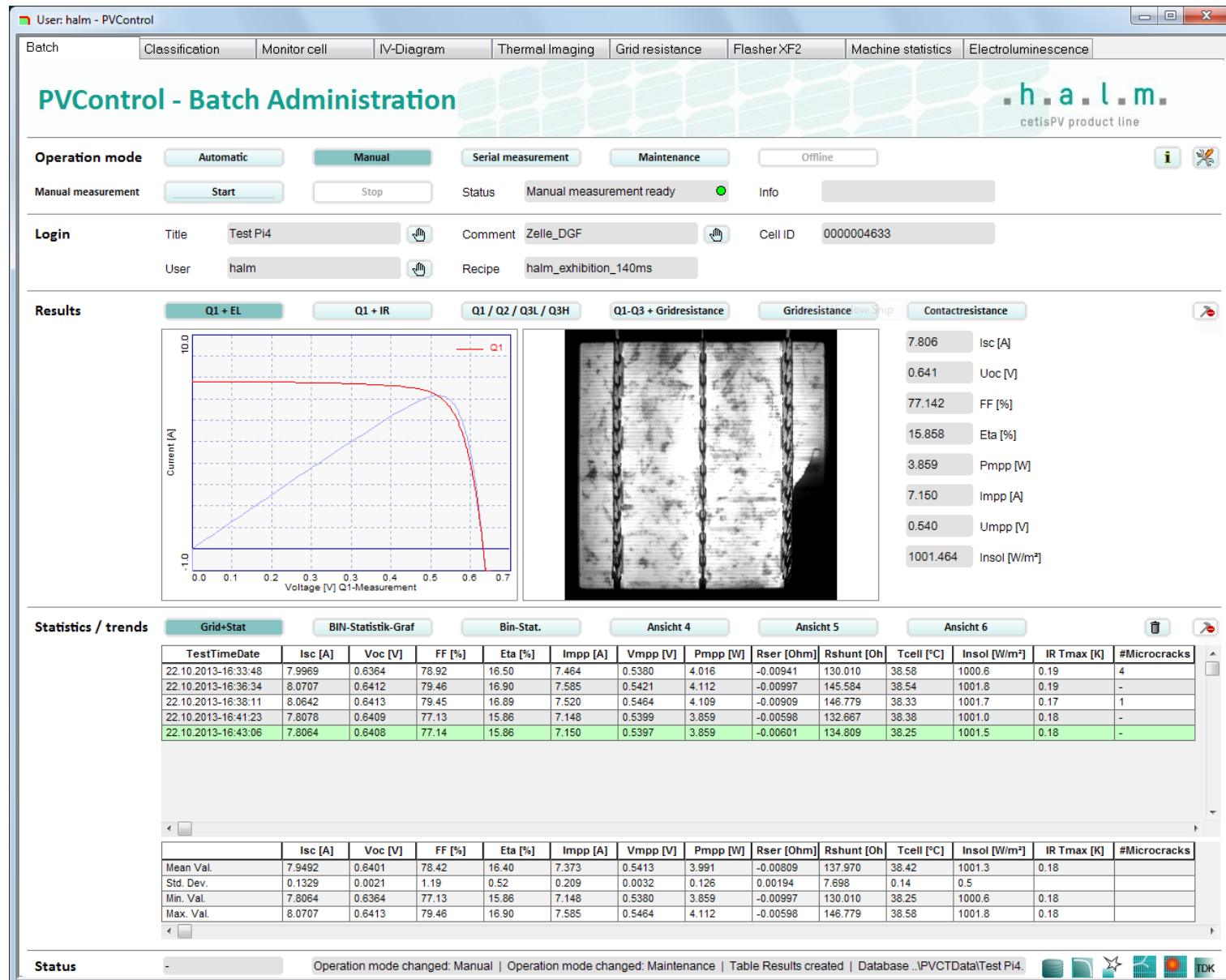
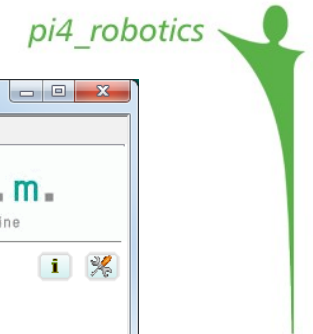


Investigation of single cells with defects



Pmpp=4.109 W

Investigation of single cells with defects



$P_{mpp}=3.859 \text{ W}$

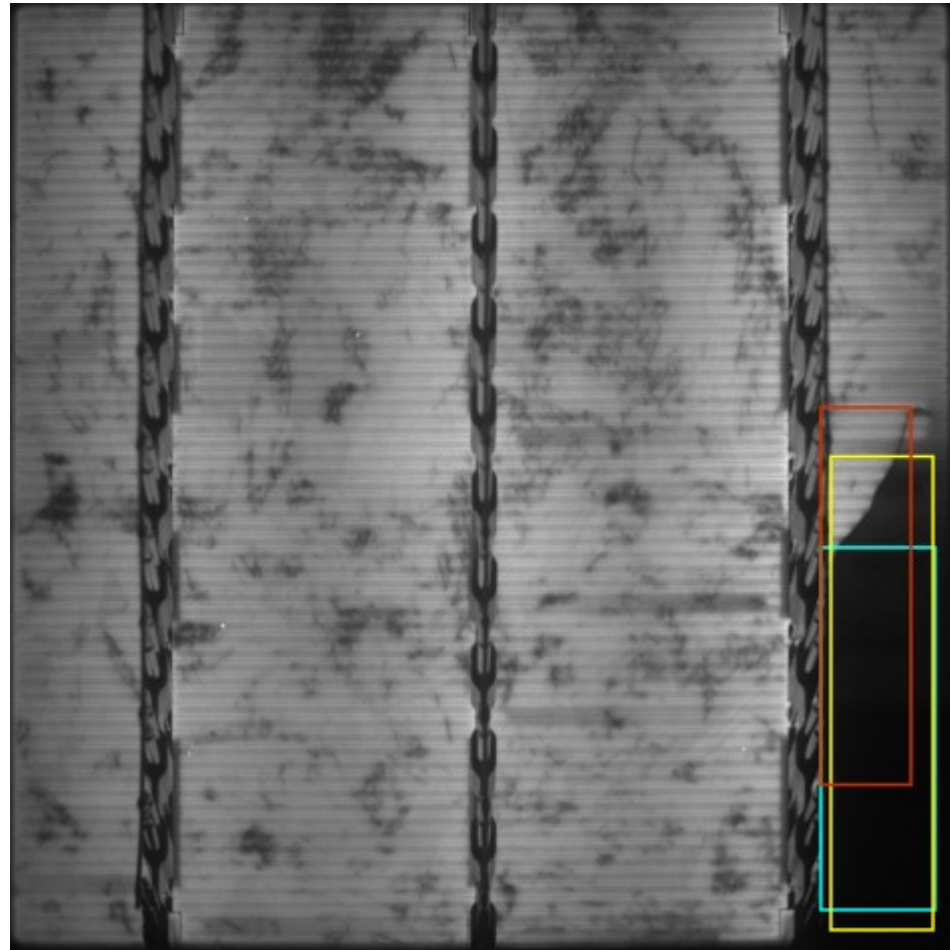
Degradation =
6.084 % of cell
power

EL evaluation of cell with crack



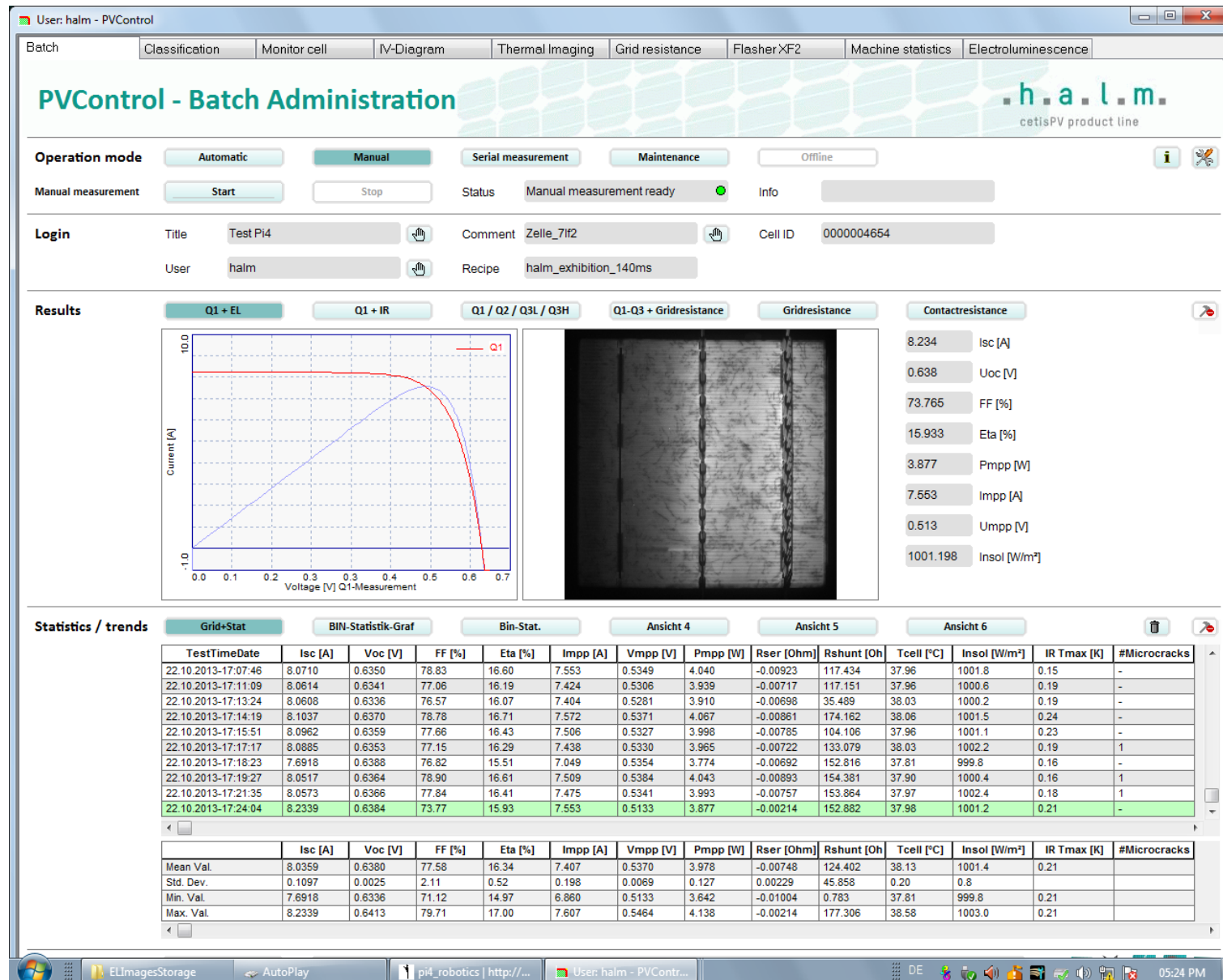
Estimated power loss of cell : 7.21 %

Deviation from flasher result : 1.13 %



Investigation of cell with busing solder error

pi4_robotics



Pmpp=4.043 W
undamaged

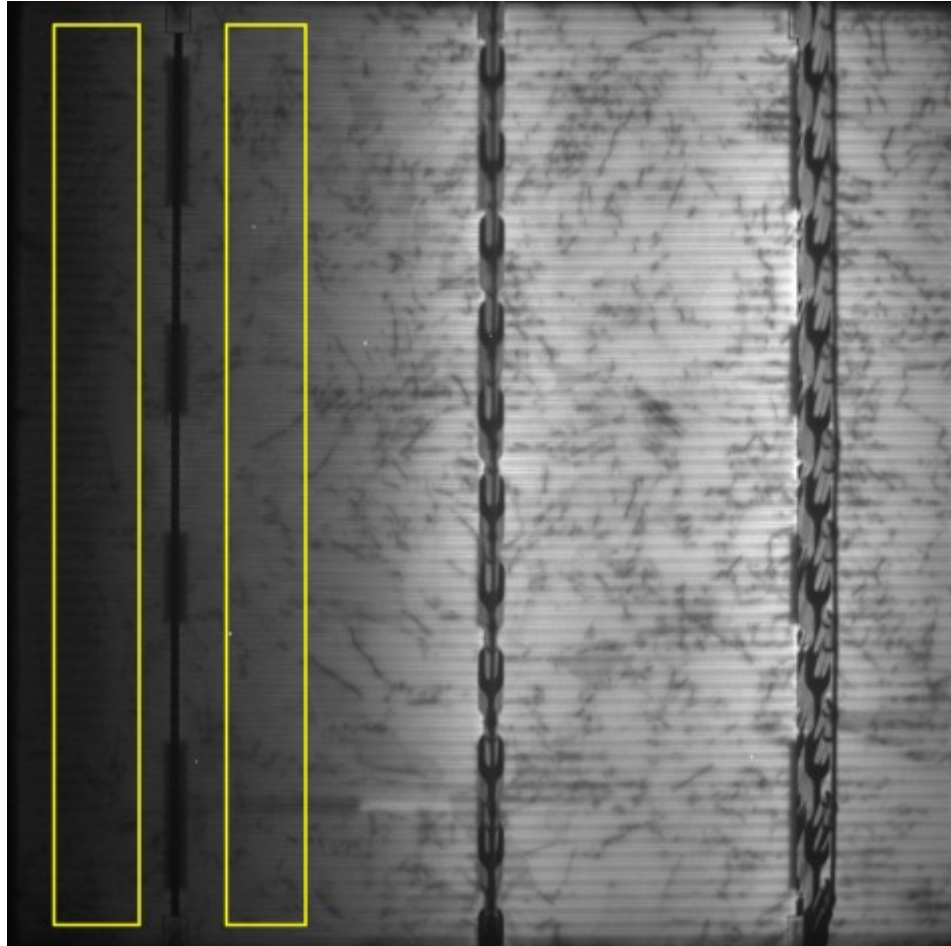
Pmpp=3.859 W with
solder error

Degradation =
4.106% of cell power

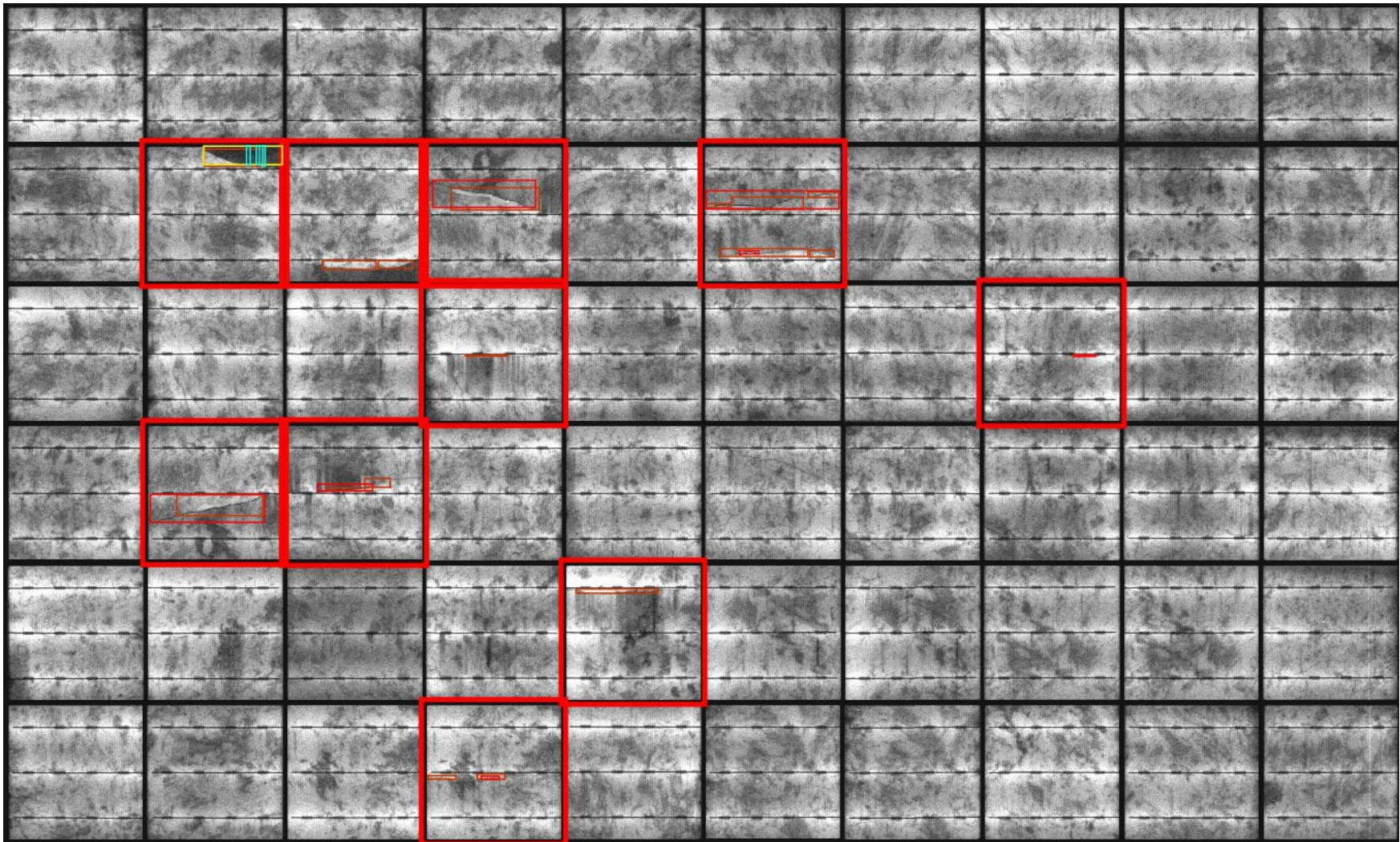
EL evaluation of cell with busing solder error

Estimated power loss of cell : 4,418 %

Deviation from flasher result : 0.312 %



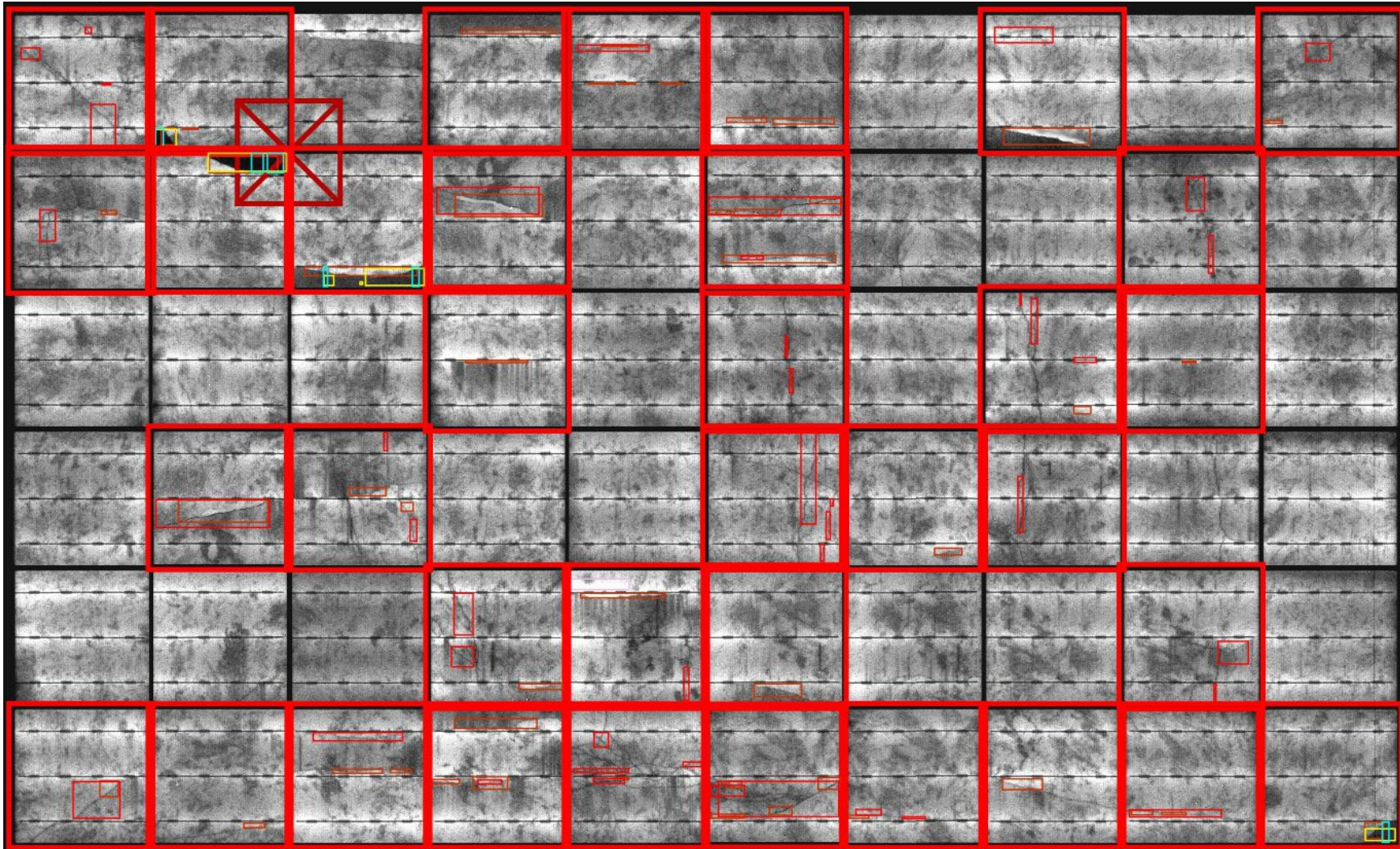
Investigation of a complete module with defects



$P_{mpp}=235\text{ W}$

(Raw EL image and flash data supplied by courtesy of TÜV Rheinland)

Investigation of a complete module with defects



After mechanical load test 5.400 Pa $P_{mpp}=232,5\text{ W}$
Power degradation = 1.1 %
Estimated Power loss = 1.25 % **Deviation from flash test = 0.15%**

Investigation of a complete module with defects

pi4_control 9.0 - Module EL Inspection

User: Administrator | Operation mode: MANUAL | Current product: sample mono 60 28B aeval T

>> Matrix view Combined image Dark I-V curve IR (hotspot) [Station 0] System [Station 1] Conveyor system [Station 2] Camera system / EL / I-V Product management System setup Hardware status Info

Cell images

Load... Save... Inspection

Combined image

Defect marker: ☒ Save...

Selection

Cell << >>

Defect << >>

Failure: R:00 | C:00
Message:

Classifier Message: **PL1=3.80 percent of module power, exceeds limit (3.00)!**

Data: PL3 summed per double string := {
[0] = 2.149; [1] = 2.996; [2] = 1.665;
}

11/02 - 19:17:46 MESSAGE: PL3=62.74 percent of module power, exceeds limit (20.00)!

11/02 - 19:17:46 MESSAGE: PL2=11.98 percent of module power, exceeds limit (10.00)!

11/02 - 19:17:46 MESSAGE: PL1=3.80 percent of module power, exceeds limit (3.00)!

Cell finder
Brightness classi
Bright regions
Microcracks
Active Cracks
Dark spots
Dark gridfinger
Finger defects

Image view 0° 50% 0 255 x/y: 660/80 - R/G/B: 20/20/20

PL1 = 3.80 %
PL2 = 11.98 %
PL3 = 62.74 %

Conergy module with rated power of 175 W flashed in Schletter Mobile PV Lab Mpp=170.7 W
Estimated Power loss = 3.8 % = 6.65 W
Deviation from flash test = -2.35 W or -1.3 %

Investigation of a complete module with defects

pi4_control 9.0 - Module EL Inspection

User: Administrator | Operation mode: MANUAL | Current product: sample mono 60 2BB

>> Matrix view Combined image Dark I-V curve IR (hotspot) [Station 0] System [Station 1] Conveyor system [Station 2] Camera system / EL / I-V Product management System setup Hardware status Info

Cell images

Load... Save... Inspection

Combined image

Defect marker: ☒ Save...

Selection

Cell << >>

Defect << >>

Image view 0° 50% 0 255 x/y: 20/154 - R/G/B: 25/25/25

Classifier Message: PL3=40.39 percent of module power, exceeds limit (20.00)!

```
Data "PL2" := {
  [0] = 7.042;
}
Data "PL1" := {
  [0] = 0.073;
}
```

PL1 = 0.07 %
PL2 = 7.04 %
PL3 = 40.39 %

The same module with the three most seriously damaged cells replaced

Conclusions

- Estimation of power loss from high resolution EL images is possible within an accuracy of $\pm 2.5\%$
- By knowing the significance of damages to the potential power loss, automatic decisions may be taken about pre lamination repair
- Not all cells with cracks necessarily have to be removed in pre lamination repair.
- Yield loss can be reduced by doing less pre lamination repair.
- Yield loss can be reduced by better knowledge of upstream machine's service state; service messages give dedicated warnings to the operators.
- With the help of automated high resolution EL inspection the cost per Wp may be reduced by more than 0.15 €cent.



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